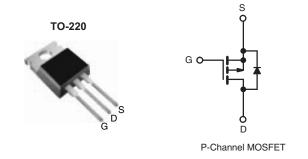




Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	0.30		
Q _g (Max.) (nC)	38			
Q _{gs} (nC)	6.8			
Q _{gd} (nC)	21			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION



The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF9530PbF
	SiHF9530-E3
SnPb	IRF9530
	SiHF9530

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, ur	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	- 100	V	
Gate-Source Voltage			V_{GS}	± 20	7 Y	
Continuous Drain Current	V _{GS} at - 10 V	T _C = 25 °C		- 12		
		T _C = 100 °C	I _D	- 8.2	A	
Pulsed Drain Current ^a			I _{DM}	- 48	1	
Linear Derating Factor				0.59	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	400	mJ	
Repetitive Avalanche Current ^a			I _{AR}	- 12	Α	
Repetitive Avalanche Energy ^a			E _{AR}	8.8	mJ	
Maximum Power Dissipation	$T_C = 3$	25 °C	P_{D}	88	W	
Peak Diode Recovery dV/dt ^c			dV/dt	- 5.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	00	
Soldering Recommendations (Peak Temperature)	for 10 s		_	300 ^d	°C	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = -25 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 4.2 \,\text{mH}$, $R_G = 25 \,\Omega$, $I_{AS} = -12 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le$ 12 A, $dI/dt \le$ 140 A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le$ 175 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRF9530, SiHF9530

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.7		

PARAMETER	SYMBOL	TEST	TEST CONDITIONS			MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$	- 100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I _D = - 1 mA	-	- 0.10	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	' _{GS} , I _D = - 250 μA	- 2.0	-	- 4.0	V
Gate-Source Leakage	I _{GSS}	Vo	_{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = - 100 V, V _{GS} = 0 V V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 150 °C		-	- 100 - 500	μΑ
Drain-Source On-State Resistance		$V_{DS} = -80 \text{ V},$ $V_{GS} = -10 \text{ V}$	$I_D = -7.2 \text{ A}^b$	-	-	0.30	
Forward Transconductance	R _{DS(on)}		I _D = - 7.2 A ^b 50 V, I _D = - 7.2 A ^b	3.7	-	0.30	Ω
	9 _{fs}	V _{DS} = - 3	50 V, I _D = - 7.2 A ²	3.7	-	-	S
Dynamic		T		_	000	l <u>-</u>	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		860	-	pF
Output Capacitance	C _{oss}	V _{DS} = - 25 V, f = 1.0 MHz, see fig. 5		-	340	-	
Reverse Transfer Capacitance	C _{rss}			-	93	-	
Total Gate Charge	Qg		$V_{GS} = -10 \text{ V}$ $I_D = -12 \text{ A}, V_{DS} = -80 \text{ V},$ see fig. 6 and 13 ^b	-	-	38	nC
Gate-Source Charge	Q _{gs}	$V_{GS} = -10 \text{ V}$		-	-	6.8	
Gate-Drain Charge	Q_{gd}			-	-	21	
Turn-On Delay Time	t _{d(on)}			-	12	-	_
Rise Time	t _r	V_{DD} = - 50 V, I_{D} = - 12 A, R_{G} = 12 Ω , R_{D} = 3.9 Ω , see fig. 10 ^b		-	52	-	- ns
Turn-Off Delay Time	t _{d(off)}			-	31	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L_D	, ,	Between lead, 6 mm (0.25") from		4.5	-	الم
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s					<u>'</u>	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 12	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	- 48	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = - 12 A, V _{GS} = 0 V ^b		-	-	- 6.3	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = -12 \text{ A}, dI/dt = 100 \text{ A/}\mu\text{s}^b$		-	120	240	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.46	0.92	μС
Forward Turn-On Time	t _{on}	Intrinsic turi	on is dor	ninatad b	ıl - and l	· ·	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

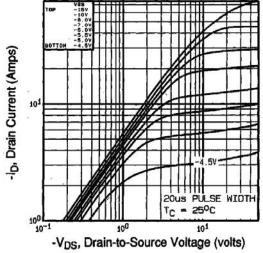


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

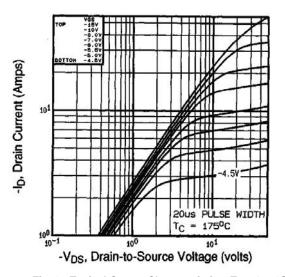


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

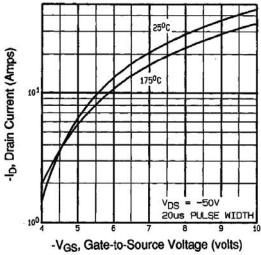


Fig. 3 - Typical Transfer Characteristics

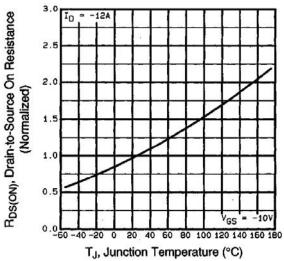


Fig. 4 - Normalized On-Resistance vs. Temperature

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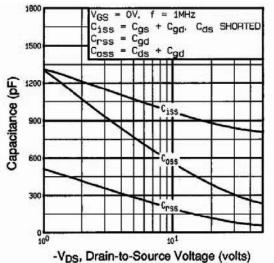
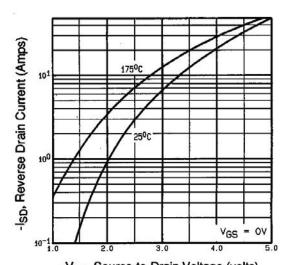


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



-V_{SD}, Source-to-Drain Voltage (volts)
Fig. 7 - Typical Source-Drain Diode Forward Voltage

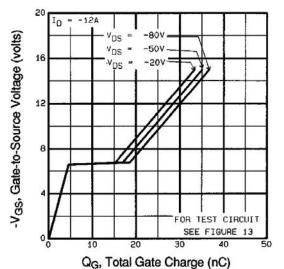
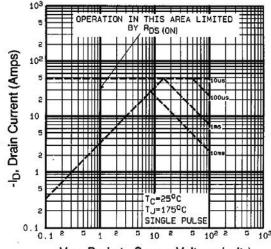


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



-V_{DS}, Drain-to-Source Voltage (volts) Fig. 8 - Maximum Safe Operating Area





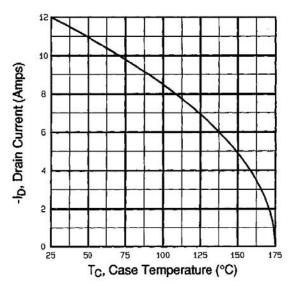


Fig. 9 - Maximum Drain Current vs. Case Temperature

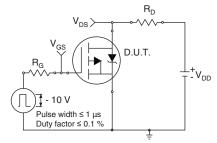


Fig. 10a - Switching Time Test Circuit

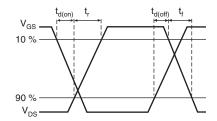


Fig. 10b - Switching Time Waveforms

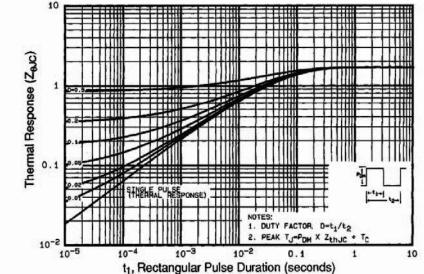


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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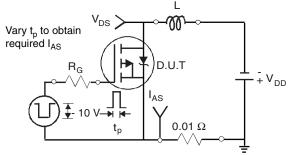


Fig. 12a - Unclamped Inductive Test Circuit

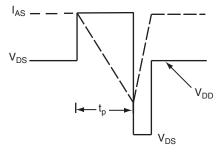


Fig. 12b - Unclamped Inductive Waveforms

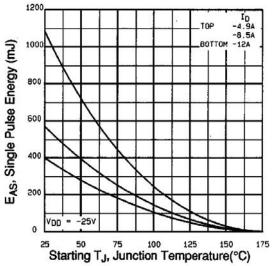


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

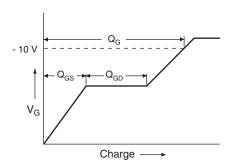


Fig. 13a - Basic Gate Charge Waveform

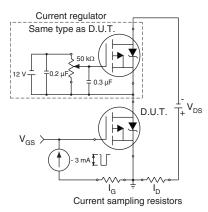
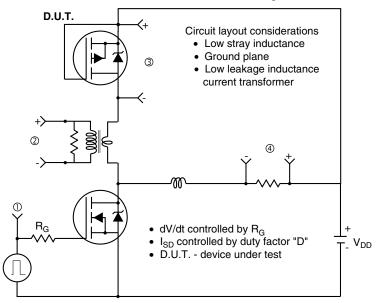


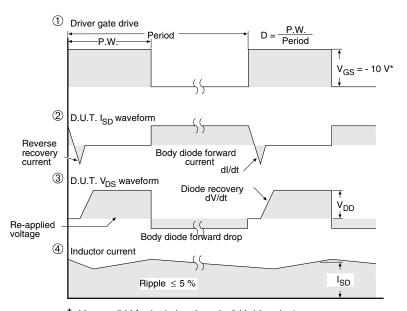
Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



 * V_{GS} = -5 V for logic level and -3 V drive devices

Fig. 14 - For P-Channel

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